

Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/564,587
				Filing Date	September 27, 2006
				First Named Inventor	Peter T. Doughty
				Art Unit	2612
				Examiner Name	D. W. Goins
Sheet	1	of	1	Attorney Docket Number	39605-501N01US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	A*	US-20010001562	05-24-2001	ORAVA et al.	
	B*	US-20030069002	04-10-2003	Hunter et al.	
	C*	US-5,812,191	09-22-1998	Orava et al.	
	D*	US-5,986,276	11-16-1999	Labriola, II	
	E*	US-6,100,806	08-08-2000	Gaukel	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	F	JP-2000206259-A (English Abstract Included)	07-28-2000	Fuji Photo Film Co Ltd		
	G	JP-2002350551-A (English Abstract Included)	12-04-2002	Canon Kk		
	H	WO-2002063339-A1	08-15-2002	Univ Glasgow et al.		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	I	Eisen, "Current state-of-the-art industrial and research applications using room-temperature CdTe and CdZnTe solid state detectors", <i>Nuclear Instruments & Methods in Physics</i> , 380(1-2):431-439 (1996)	
	J	Schwarz et al., "Measurements with Si and GaAs pixel detectors bonded to photon counting readout chips", <i>Nuclear Instruments & Methods in Physics Research</i> , 466(1):87-94 (2001)	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. * CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.